


|  |  |  |
|--|--|--|
| <b>Search Notes</b><br><br> | <b>Application/Control No.</b><br><br>10562094 | <b>Applicant(s)/Patent Under Reexamination</b><br><br>HAYASHI ET AL. |
|  | <b>Examiner</b><br><br>ANISH DESAI             | <b>Art Unit</b><br><br>1794  |

| SEARCHED |          |      |          |
|----------|----------|------|----------|
| Class    | Subclass | Date | Examiner |
|          |          |      |          |

| SEARCH NOTES  |           |          |
|---|-----------|----------|
| Search Notes  | Date      | Examiner |
| Text search using EAST (all databases except USOCR) | 3/13/2009 | APD      |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

|  |  |
|--|--|
|  |  |
|--|--|